

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Process

IECQ Certificate No.: IECQ-L ULTW 16.0003-04
CB Certificate No.: 20003698 ITL

Schedule Number: IECQ-L ULTW 16.0003-04-S Rev No.: 5 Revision Date: 2020/08/19 Page 1 of 3

Appendix-1 (20003698 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard		
Latch-up	JESD78		
НВМ	JS-001		
ММ	JS-001		
СДМ	JS-002		
ESD Gun	IEC 61000-4-2		
EOS	IEC 61000-4-5		
TLP	ESDA		
Wire Bonding	NA		
IC Package	NA		
Pull and shear test	MIL-STD-883 method 2011.9 MIL-STD-883 method 2023.7 AEC-100-001 EIA/JESD22-B116 JESD22-B117		
High Temperature Operation Life test (HTOL)	JESD22-A108, IEC 60068-2-1		
Low Temperature Operation Life test (LTOL)	JESD22-A108, IEC 60068-2-1		
Bias Life test (BLT)	JESD22-A108		
Temperature Cycling test (TCT)	JESD22-A104		

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Temperature variation test (TCC)	IEC 60068-2-14/33
Thermal Shock test (TST)	JESD22-A106
High Temperature Storage test (HTST)	IEC 60068-2-2
Low Temperature Storage test (LTST)	IEC 60068-2-1
Pressure Cooker test (PCT/UB-HAST)	JESD22-A102
Highly Accelerated Stress test (HAST)	JESD22-A110
Temperature and Humidity Storage test (THST)	IEC 60068-2-3
Temperature and Humidity with Bias test (THB)	JEDEC22 A101
Pre-conditioning test	JESD22-A113
Reflow test	J-STD-020
Solderability test	J-STD-002
Steam aging test	J-STD-002
SMT	IPC-A-610
Multi-function material test(Bending test)	JESD22-B113
Drop test	ISTA 2A, IEC 60068-2-32
Vibration test and Shock Test	IEC 60068-2-6/27/29/34/64
Salt atmosphere street test	JESD22-A107, IEC 60068-2-11/52
Gas corrosion test	IEC 60068-2-42/43/49/60
Electro-migration test	IPC TM650 2.6.25
Conductive resistance test	IPC 9701

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Low temperature/ low humidity test	IEC 6006	8-2-38/39	
Low pressure / altitude test	IEC 60068	B-2-13	
Dust and water proof test	IEC60529		
Solar radiation test	IEC 6006	B-2-5/9	
Tumbling Test	IEC 6006	8-2-31	

Technical Reviewer of DQS: Michael Chou Date: 8/19/2020

